# <sup>63</sup>Ni in beta voltaic battery

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# 1. Introduction

A nuclear battery with diode junction is a device that converts nuclear radiation directly to electric power [2]. In betavoltaic battery, beta particles are collected and converted to electrical energy as similar principle as photovoltaic. Radioactive thin-film based power source also haveen ergy density order so magnitude higher than chemical-reaction-based energy sources. The thickness dependents self shielding effect of the seed layer was studied by using both simulation using MCNP code an dmeasurement of I-Vcurve.

# 2. Experimental Results

To fabricate the P-N absorber, new type of 3D single trenched P-N absorber was developed for easy trenching and doping process. <sup>63</sup>Ni can be deposited and power output can be measured.

### 3. Results and discussion

Ni seed layers were deposited by an e-beam on the single trench P-N absorber with spacing 5, 110 and 190 mm. The optimum total thickness of <sup>63</sup>Ni and seed layer was determined about  $2\mu$ m as regarding the minimum self-shielding effec to beta-ray( $\beta$ -ray). Both the conductivity and the uniformity of the seed layer are enhanced, as the thickness of deposit layer is increased. However, self-shielding of  $\beta$ -ray is significantly increased, as the thickness of the seed layer become thick. To fabricate effective battery, the thickness of seed layer about 500 Å have been determined.

# 4. Conclusion

Ni seed layers were deposited by an e-beam on the single trench P-N absorber with spacing 5, 110 and 190 mm. The optimum total thickness of  $^{63}$ Ni and seed layer was determined about 2µm. To fabricate effective  $\beta$ -voltaic battery, the thickness of seed layer about 500 Å have been determined.

### 5. Reference

[1] J. Ulmen B, Desai PD, Moghaddam, Miley GH, Massel RI (2009) J. Radioanal Nucl. Chem 282:601